Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/573,981	OKUMURA ET AL.
Examiner	Art Unit

Christian A. Hannon

2618

SEARCHED				
Class	Subclass	Date	Examiner	
455	151.1	8/31/2007	СН	
455	154.1	8/31/2007		
455	157.1	8/31/2007		
455	157.2	8/31/2007		
455	158.1	8/31/2007		
455	158.2	8/31/2007		
455	158.4	8/31/2007		
455	158.5	8/31/2007		
455	159.1	8/31/2007		
455	179.1	8/31/2007		
455	180.1	8/31/2007		
455	184.1	8/31/2007		
455	186.1	8/31/2007		
455	345	8/31/2007	6	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Consulted E. Urban, See printout	8/31/2007	СН	
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